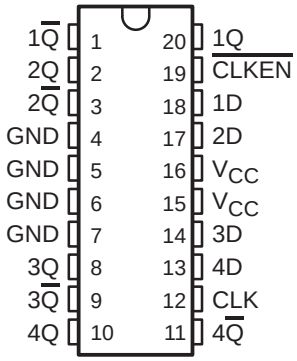
- **Inputs Are TTL-Voltage Compatible**
- **Contains Four Flip-Flops with Double-Rail Outputs**
- **Clock Enable Latched to Avoid False Clocking**
- **Applications Include: Buffer/Storage Registers, Shift Registers, Pattern Generators**
- **Flow-Through Architecture to Optimize PCB Layout**
- **Center-Pin $V_{CC}$ and GND Configurations to Minimize High-Speed Switching Noise**
- **EPIC™ (Enhanced-Performance Implanted CMOS) 1-μm Process**
- **500-mA Typical Latch-Up Immunity at 125°C**
- **Package Options Include Plastic Small Outline Packages, and Standard Plastic 300-mil DIPs**

**DW OR N PACKAGE**

**(TOP VIEW)**




## description

These circuits are positive-edge-triggered D-type flip-flops with a clock-enable input.

Information at the D inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if $\overline{\text{CLKEN}}$ is low. Clock triggering occurs at a particular voltage level and is not directly related to the transition time of the positive-going pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output. The circuits are designed to prevent false clocking by transitions at the $\overline{\text{CLKEN}}$ input.

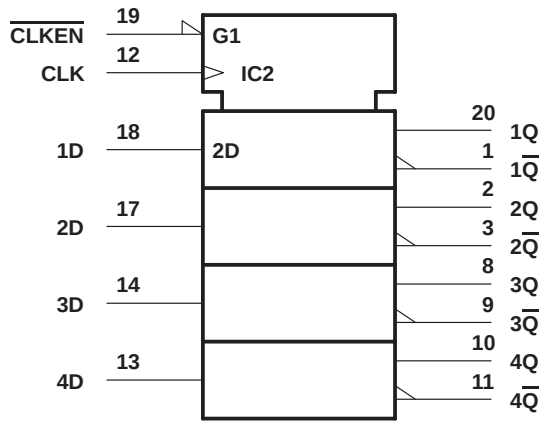
The 74ACT11379 is characterized for operation from – 40°C to 85°C.

**FUNCTION TABLE**
**(each flip-flop)**

| INPUTS | | | OUTPUTS | |
|---|---|---|---|---|
| $\overline{\text{CLKEN}}$ | CLK | D | Q | $\overline{\text{Q}}$ |
| H | X | X | $Q_0$ | $\overline{Q}_0$ |
| L | ↑ | H | H | L |
| L | ↑ | L | L | H |
| X | L | X | $Q_0$ | $\overline{Q}_0$ |

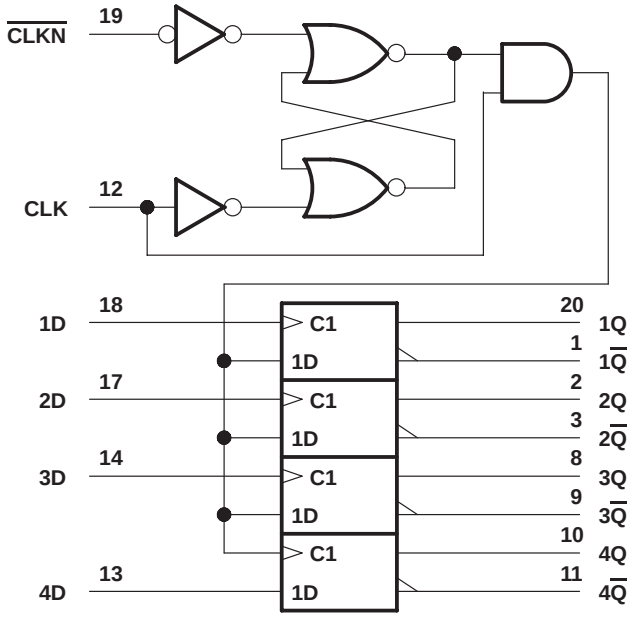
EPIC is a trademark of Texas Instruments Incorporated.

## logic symbol†




† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## logic diagram (positive logic)




## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, $V_{CC}$ . . . . . – 0.5 V to 7 V
Input voltage range, $V_I$ (see Note 1) . . . . . – 0.5 V to $V_{CC}$ + 0.5 V
Output voltage range, $V_O$ (see Note 1) . . . . . – 0.5 V to $V_{CC}$ + 0.5 V
Input clamp current, $I_{IK}$ ($V_I$ < 0 or $V_I$ > $V_{CC}$) . . . . . ± 20 mA
Output clamp current, $I_{OK}$ ($V_O$ < 0 or $V_O$ > $V_{CC}$) . . . . . ± 50 mA
Continuous output current, $I_O$ ($V_O$ = 0 to $V_{CC}$) . . . . . ± 50 mA
Continuous current through $V_{CC}$ or GND . . . . . ± 200 mA
Storage temperature range . . . . . – 65°C to 150°C

‡ Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## recommended operating conditions

| | | MIN | MAX | UNIT |
|---|---|---|---|---|
| $V_{CC}$ | Supply voltage | 4.5 | 5.5 | V |
| $V_{IH}$ | High-level input voltage | 2 | | V |
| $V_{IL}$ | Low-level input voltage | | 0.8 | V |
| $V_I$ | Input voltage | 0 | $V_{CC}$ | V |
| $V_O$ | Output voltage | 0 | $V_{CC}$ | V |
| $I_{OH}$ | High-level output current | | –24 | mA |
| $I_{OL}$ | Low-level output current | | 24 | mA |
| $\Delta t/\Delta v$ | Input transition rise or fall rate | 0 | 10 | ns/V |
| $T_A$ | Operating free-air temperature | – 40 | 85 | °C |

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS | $V_{CC}$ | $T_A$ = 25°C | | | MIN | MAX | UNIT |
|---|---|---|---|---|---|---|---|---|
| | | | MIN | TYP | MAX | | | |
| $V_{OH}$ | $I_{OH}$ = – 50 μA | 4.5 V | 4.4 | | | 4.4 | | V |
| | | 5.5 V | 5.4 | | | 5.4 | | |
| | $I_{OH}$ = – 24 mA | 4.5 V | 3.94 | | | 3.8 | | |
| | | 5.5 V | 4.94 | | | 4.8 | | |
| | $I_{OH}$ = – 75 mA† | 5.5 V | | | | 3.85 | | |
| $V_{OL}$ | $I_{OL}$ = 50 μA | 4.5 V | | | 0.1 | | 0.1 | V |
| | | 5.5 V | | | 0.1 | | 0.1 | |
| | $I_{OL}$ = 24 mA | 4.5 V | | | 0.36 | | 0.44 | |
| | | 5.5 V | | | 0.36 | | 0.44 | |
| | $I_{OL}$ = 75 mA† | 5.5 V | | | | | 1.65 | |
| $I_I$ | $V_I = V_{CC}$ or GND | 5.5 V | | | ± 0.1 | | ± 1 | μA |
| $I_{CC}$ | $V_I = V_{CC}$ or GND, $I_O$ = 0 | 5.5 V | | | 8 | | 80 | μA |
| $\Delta I_{CC}$‡ | One input at 3.4 V, Other inputs at GND or $V_{CC}$ | 5.5 V | | | 0.9 | | 1 | mA |
| $C_i$ | $V_I = V_{CC}$ or GND | 5 V | | 4 | | | | pF |

† Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.
‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or $V_{CC}$.

## timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

| | | | $T_A$ = 25°C | | MIN | MAX | UNIT |
|---|---|---|---|---|---|---|---|
| | | | MIN | MAX | | | |
| $f_{clock}$ | Clock frequency | | 0 | 100 | 0 | 100 | MHz |
| $t_w$ | Pulse duration | CLK high | 5 | | 5 | | ns |
| | | CLK low | 5 | | 5 | | |
| $t_{su}$ | Setup time, before CLK↑ | Data | 5 | | 5 | | ns |
| | | $\overline{\text{CLKEN}}$ high | 3.5 | | 3.5 | | |
| | | $\overline{\text{CLKEN}}$ low | 3.5 | | 3.5 | | |
| $t_h$ | Hold time, after CLK ↑ | $\overline{\text{CLKEN}}$ inactive or active, data | 0 | | 0 | | ns |

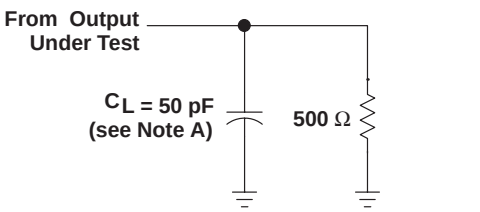
## switching characteristics over recommended ranges of supply voltage and operating free-air temperature range (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | $T_A$ = 25°C | | | MIN | MAX | UNIT |
|---|---|---|---|---|---|---|---|---|
| | | | MIN | TYP | MAX | | | |
| $f_{max}$ | | | 100 | 125 | | 100 | | MHz |
| $t_{PLH}$ | CLK | Any Q or $\overline{Q}$ | 2.2 | 5 | 6.6 | 2.2 | 7.4 | ns |
| $t_{PHL}$ | | | 3.1 | 7.2 | 9.8 | 3.1 | 11.2 | |

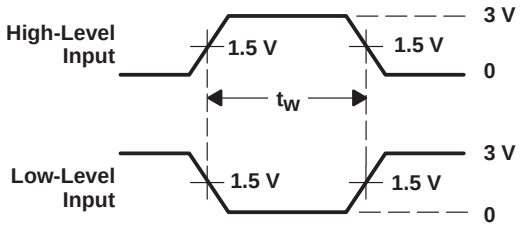
## operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

| PARAMETER | | TEST CONDITIONS | TYP | UNIT |
|---|---|---|---|---|
| $C_{pd}$ | Power dissipation capacitance | $C_L$ = 50 pF, f = 1 MHz | 38 | pF |

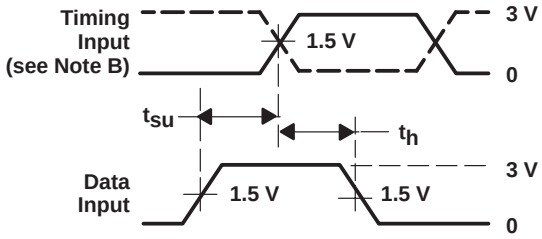
## PARAMETER MEASUREMENT INFORMATION



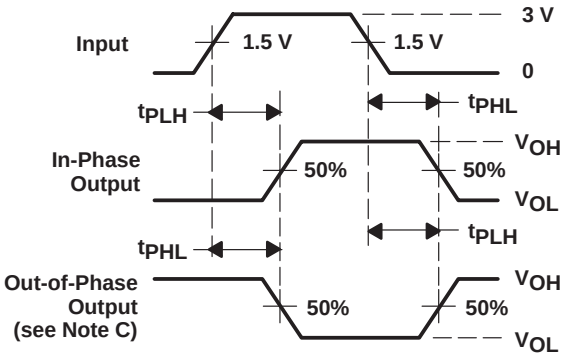

LOAD CIRCUIT




VOLTAGE WAVEFORMS
PULSE DURATIONS




SETUP AND HOLD TIMES




PROPAGATION DELAY TIMES

NOTES: A. $C_L$ includes probe and jig capacitance.
B. Input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, $Z_O$ = 50 Ω, $t_r$ = 3 ns, $t_f$ = 3 ns.
C. The outputs are measured one at a time with one input transition per measurement.

**Figure 1. Load Circuit and Voltage Waveforms**

## IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.